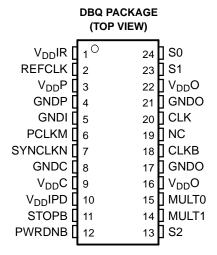


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DIRECT RAMBUS™ CLOCK GENERATOR

FEATURES

- 533-MHz Differential Clock Source for Direct Rambus™ Memory Systems for an 1066-MHz Data Transfer Rate
- Fail-Safe Power Up Initialization
- Synchronizes the Clock Domains of the Rambus Channel With an External System or Processor Clock
- Three Power Operating Modes to Minimize Power for Mobile and Other Power-Sensitive Applications
- Operates From a Single 3.3-V Supply and 120 mW at 300 MHz (Typ)
- Packaged in a Shrink Small-Outline Package (DBQ)
- Supports Frequency Multipliers: 4, 6, 8, 16/3
- No External Components Required for PLL
- Supports Independent Channel Clocking
- Spread Spectrum Clocking Tracking Capability to Reduce EMI
- Designed for Use With TI's 133-MHz Clock Synthesizers CDC924 and CDC921
- Cycle-Cycle Jitter Is Less Than 40 ps at 533 MHz
- Certified by Gigatest Labs to Exceed the Rambus DRCG Validation Requirement
- Supports Industrial Temperature Range of –40°C to 85°C



NC - No internal connection

DESCRIPTION

The Direct Rambus clock generator (DRCG) provides the necessary clock signals to support a Direct Rambus memory subsystem. It includes signals to synchronize the Direct Rambus channel clock to an external system or processor clock. It is designed to support Direct Rambus memory on a desktop, workstation, server, and mobile PC motherboards. DRCG also provides an off-the-shelf solution for a broad range of Direct Rambus memory applications.

The DRCG provides clock multiplication and phase alignment for a Direct Rambus memory subsystem to enable synchronous communication between the Rambus channel and ASIC clock domains. In a Direct Rambus memory subsystem, a system clock source provides the REFCLK and PCLK clock references to the DRCG and memory controller, respectively. The DRCG multiplies REFCLK and drives a high-speed BUSCLK to RDRAMs and the memory controller. Gear ratio logic in the memory controller divides the PCLK and BUSCLK frequencies by ratios M and N such that PCLKM = SYNCLKN, where SYNCLK = BUSCLK/4. The DRCG detects the phase difference between PCLKM and SYNCLKN and adjusts the phase of BUSCLK such that the skew between PCLKM and SYNCLKN is minimized. This allows data to be transferred across the SYNCLK/PCLK boundary without incurring additional latency.

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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User control is provided by multiply and mode selection terminals. The multiply terminals provide selection of one of four clock frequency multiply ratios, generating BUSCLK frequencies ranging from 267 MHz to 533 MHz with clock references ranging from 33 MHz to 100 MHz. The mode select terminals can be used to select a bypass mode where the frequency multiplied reference clock is directly output to the Rambus channel for systems where synchronization between the Rambus clock and a system clock is not required. Test modes are provided to bypass the PLL and output REFCLK on the Rambus channel and to place the outputs in a high-impedance state for board testing.

The CDCFR83A has a fail-safe power up initialization state-machine which supports proper operation under all power up conditions.

The CDCFR83A is characterized for operation over free-air temperatures of -40°C to 85°C.

FUNCTIONAL BLOCK DIAGRAM PWRDWNB S0 S2 **STOPB Test MUX Bypass MUX ByPCLK PLLCLK** CLK PLL Phase **CLKB REFCLK** В Aligner **PACLK** $\varphi_{\boldsymbol{D}}$ 2 PCLKM | SYNCLKN **MULTO**

FUNCTION TABLE(1)

| MODE | S0 | S 1 | S2 | CLK | CLKB |
|------------------|----|------------|----|---------------------|-----------------------|
| Normal | 0 | 0 | 0 | Phase aligned clock | Phase aligned clock B |
| Bypass | 1 | 0 | 0 | PLLCLK | PLLCLKB |
| Test | 1 | 1 | 0 | REFCLK | REFCLKB |
| Output test (OE) | 0 | 1 | Х | Hi-Z | Hi-Z |
| Reserved | 0 | 0 | 1 | _ | _ |
| Reserved | 1 | 0 | 1 | _ | _ |
| Reserved | 1 | 1 | 1 | Hi-Z | Hi-Z |

(1) X = don't care, Hi-Z = high impedance

MULT1



TERMINAL FUNCTIONS

| TERMINAL | | | DECODINE | |
|---------------------|--------|-----|---|--|
| NAME | NO. | I/O | DESCRIPTION | |
| CLK | 20 | 0 | Output clock | |
| CLKB | 18 | 0 | Output clock (complement) | |
| GNDC | 8 | | GND for phase aligner | |
| GNDI | 5 | | GND for control inputs | |
| GNDO | 17, 21 | | GND for clock outputs | |
| GNDP | 4 | | GND for PLL | |
| MULT0 | 15 | I | PLL multiplier select | |
| MULT1 | 14 | I | PLL multiplier select | |
| NC | 19 | | Not used | |
| PCLKM | 6 | ı | Phase detector input | |
| PWRDNB | 12 | _ | Active low power down | |
| REFCLK | 2 | I | Reference clock | |
| S0 | 24 | I | Mode control | |
| S1 | 23 | I | Mode control | |
| S2 | 13 | _ | Mode control | |
| STOPB | 11 | _ | Active low output disable | |
| SYNCLKN | 7 | I | Phase detector input | |
| $V_{DD}C$ | 9 | | V _{DD} for phase aligner | |
| V _{DD} IPD | 10 | | Reference voltage for phase detector inputs and STOPB | |
| $V_{DD}IR$ | 1 | | Reference voltage for REFCLK | |
| V _{DD} O | 16, 22 | | V _{DD} for clock outputs | |
| $V_{DD}P$ | 3 | | V _{DD} for PLL | |



PLL DIVIDER SELECTION

Table 1 lists the supported REFCLK and BUSCLK frequencies. Other REFCLK frequencies are permitted, provided that (267 MHz < BUSCLK < 533 MHz) and (33 MHz < REFCLK < 100 MHz).

Table 1. REFCLK and BUSCLK Frequencies

| MULT0 | MULT1 | REFCLK (MHz) | MULTIPLY RATIO | BUSCLK ⁽¹⁾ (MHz) |
|-------|-------|-----------------|-------------------|--------------------------------|
| 0 | 0 | 67 | 4 | 267 |
| 0 | 1 | 50 | 6 | 300 |
| 0 | 1 | 67 | 6 | 400 |
| 1 | 1 | 33 | 8 | 267 |
| 1 | 1 | 50 | 8 | 400 |
| 1 | 1 | 67 | 8 | 533 |
| 1 | 0 | 67 | 16/3 | 356 |

⁽¹⁾ BUSCLK will be undefined until a valid reference clock is available at REFCLK. After applying REFCLK, the PLL requires stabilization time to achieve phase lock.

Table 2. Clock Output Driver States

| STATE | PWRDNB | STOPB | CLK | CLKB |
|-----------|--------|-------|------------------------------------|------------------------|
| Powerdown | 0 | X | GND | GND |
| CLK stop | 1 | 0 | V _{X, STOP} | $V_{X, STOP}$ |
| Normal | 1 | 1 | PACLK/PLLCLK/REFCLK ⁽¹⁾ | PACLKB/PLLCLKB/REFCLKB |

⁽¹⁾ Depending on the state of S0, S1, and S2

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)(1)

| | | UNIT |
|------------------|--|-----------------------------------|
| V_{DD} | Supply voltage range ⁽²⁾ | –0.5 V to 4 V |
| Vo | Output voltage range at any output terminal | -0.5 V to V _{DD} + 0.5 V |
| V_{I} | Input voltage rangeat any input terminal | –0.5 V to V _{DD} + 0.5 V |
| | Continuous total power dissipation | See Dissipation Rating Table |
| T_A | Operating free-air temperature range | -40°C to 85°C |
| T _{stg} | Storage temperature range | −65°C to 150°C |
| | Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds | 260°C |

⁽¹⁾ Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

DISSIPATION RATINGS

| PACKAGE | T _A ≤ 25°C | DERATING FACTOR | T _A = 70°C | T _A = 85°C |
|---------|-----------------------|--|-----------------------|-----------------------|
| | POWER RATING | ABOVE T _A = 25°C ⁽¹⁾ | POWER RATING | POWER RATING |
| DBQ | 1400 mW | 11 mW/°C | 905 mW | 740 mW |

⁽¹⁾ This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.

⁽²⁾ All voltage values are with respect to the GND terminals.



RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range (unless otherwise noted)

| | | MIN | NOM | MAX | UNIT |
|-----------------|---|-------------------------|-----|------------------------|------|
| V_{DD} | Supply voltage | 3.135 | 3.3 | 3.465 | V |
| V_{IH} | High-level input voltage (CMOS) | $0.7 \times V_{DD}$ | | | V |
| V_{IL} | Low-level input voltage (CMOS) | | | $0.3 \times V_{DD}$ | V |
| | Initial phase error at phase detector inputs (required range for phase aligner) | $-0.5 \times t_{c(PD)}$ | | $0.5 \times t_{c(PD)}$ | V |
| V_{IL} | REFCLK low-level input voltage | | | $0.3 \times V_{DD}IR$ | V |
| V_{IH} | REFCLK high-level input voltage | $0.7 \times V_{DD}IR$ | | | V |
| V_{IL} | Input signal low voltage (STOPB) | | | $0.3 \times V_{DD}IPD$ | V |
| V_{IH} | Input signal high voltage (STOPB) | $0.7 \times V_{DD}IPD$ | | | V |
| | Input reference voltage for (REFCLK) (V _{DD} IR) | 1.235 | | 3.465 | V |
| | Input reference voltage for (PCLKM and SYSCLKN) (V _{DD} IPD) | 1.235 | | 3.465 | V |
| I _{OH} | High-level output current | | | -16 | mA |
| I _{OL} | Low-level output current | | | 16 | mA |
| T _A | Operating free-air temperature | -40 | | 85 | °C |

TIMING REQUIREMENTS

| | | N | IIN | MAX | UNIT |
|--------------------|---|----|-----|------|------|
| t _{c(in)} | Input cycle time | | 10 | 40 | ns |
| | Input cycle-to-cycle jitter | | | 250 | ps |
| | Input duty cycle over 10,000 cycles | 40 | 0% | 60% | |
| f _{mod} | Input frequency modulation | | 30 | 33 | kHz |
| | Modulation index, nonlinear maximum 0.5% | | | 0.6% | |
| | Phase detector input cycle time (PCLKM and SYNCLKN) | | 30 | 100 | ns |
| SR | Input slew rate | | 1 | 4 | V/ns |
| | Input duty cycle (PCLKM and SYNCLKN) | 25 | 5% | 75% | |



ELECTRICAL CHARACTERISTICS

over recommended operating free-air temperature range (unless otherwise noted)

| | PARAMETE | R | TEST CON | DITIONS ⁽¹⁾ | MIN | TYP ⁽²⁾ | MAX | UNIT |
|--------------------------|---|-------------------------------------|--|---------------------------|-----------------------|--------------------|------|------|
| V _{O(STOP)} | Output voltage during | CLK Stop (STOPB = 0) | See Figure 1 | | 1.1 | | 2 | |
| $V_{O(X)}$ | Output crossing-point | voltage | See Figure 1 and F | igure 6 | 1.3 | | 1.8 | V |
| Vo | Output voltage swing | | See Figure 1 | | 0.4 | | 0.6 | V |
| V_{IK} | Input clamp voltage | | $V_{DD} = 3.135 \text{ V},$ | $I_I = -18 \text{ mA}$ | | | -1.2 | V |
| | | | See Figure 1 | | | | 2 | |
| V_{OH} | High-level output volta | age | V_{DD} = min to max, | $I_{OH} = -1 \text{ mA}$ | V _{DD} - 0.1 | | | V |
| | | | $V_{DD} = 3.135 \text{ V},$ | $I_{OH} = -16 \text{ mA}$ | 2.4 | | | |
| İ | | | See Figure 1 | | 1 | | | |
| V_{OL} | Low-level output volta | ge | V_{DD} = min to max, | $I_{OH} = 1 \text{ mA}$ | | | 0.1 | V |
| | | | $V_{DD} = 3.135 \text{ V},$ | $I_{OH} = 16 \text{ mA}$ | | | 0.5 | |
| i | | | $V_{DD} = 3.135 V,$ | $V_O = 1 V$ | -32 | – 52 | | |
| I_{OH} | High-level output curr | ent | $V_{DD} = 3.3 V,$ | $V_0 = 1.65 \text{ V}$ | | – 51 | | mA |
| | | | $V_{DD} = 3.465 \text{ V},$ | $V_0 = 3.135 \text{ V}$ | | -14.5 | -21 | |
| | | | $V_{DD} = 3.135 V,$ | $V_0 = 1.95 \text{ V}$ | 43 | 61.5 | | |
| I_{OL} | Low-level output curre | ent | $V_{DD} = 3.3 V,$ | $V_0 = 1.65 \text{ V}$ | | 65 | | mA |
| | | | $V_{DD} = 3.465 \text{ V},$ | $V_O = 0.4 V$ | | 25.5 | 36 | |
| I_{OZ} | High-impedance-state output current | | S0 = 0, S1 = 1 | | | | ±10 | μΑ |
| I _{OZ(STOP)} | High-impedance-state output current during CLK stop | | Stop = 0, $V_O = GNE$ | O or V _{DD} | | | ±100 | μΑ |
| I _{OZ(PD)} | High-impedance-state output current in power-down state | | PWRDNB = 0, V _O = | = GND or V _{DD} | -10 | | 100 | μΑ |
| | High-level input | REFCLK, PCLKM, SYNCLKN, STOPB | V 2.405.V | V V | | | 10 | |
| I _{IH} | current | PWRDNB, S0, S1, S2, MULT0, MULT1 | $V_{DD} = 3.465 \text{ V},$ | $v_I = v_{DD}$ | | | 10 | μΑ |
| | Low-level input | REFCLK, PCLKM, SYNCLKN, STOPB | V 0.405.V | | | | -10 | |
| I _{IL} | current PWRDNB, S0, S2, MULT0, M | | $V_{DD} = 3.465 \text{ V},$ | V ₁ = 0 | | | -10 | μΑ |
| 7 | Outrot increased | High state | R _I at I _O - 14.5 mA to | o –16.5 mA | 15 | 35 | 50 | |
| Z_{O} | Output impedance | Low state | R _I at I _O 14.5 mA to | 16.5 mA | 11 | 17 | 35 | Ω |
| | Defenses assument | V ID V IDD | V 2.405.V | PWRDNB = 0 | | | 50 | μΑ |
| | Reference current | $V_{DD}IR$, $V_{DD}IPD$ | $V_{DD} = 3.465 \text{ V}$ | PWRDNB = 1 | | | 0.5 | mA |
| Cı | Input capacitance | | $V_{I} = V_{DD}$ or GND | | | 2 | | pF |
| Co | Output capacitance | | $V_O = V_{DD}$ or GND | | | 3 | | pF |
| I _{DD(PD)} | Supply current in pwo | er-down state | REFCLK = 0 MHz to 100 MHz, PWDNB = 0, STOPB = 1 | | | | 100 | μΑ |
| I _{DD(CLKSTOP)} | Supply current in CLK | stop state | BUSCLK configured | d for 533 MHz | | | 45 | mA |
| I _{DD(NORMAL)} | Supply current in norr | nal state | BUSCLK = 533 MH | lz | | | 100 | mA |

 V_{DD} refers to any of the following; $V_{DD},\,V_{DD}IPD,\,V_{DD}IR,\,V_{DD}O,\,V_{DD}C,$ and $V_{DD}P$ All typical values are at V_{DD} = 3.3 V, T_A = 25°C.



SWITCHING CHARACTERISTICS

over recommended operating free-air temperature range (unless otherwise noted)

| | PARAME | TER | | TEST CONDITIONS | MIN | TYP ⁽¹⁾ MAX | UNIT |
|---------------------------------|---|----------------------|------------------------|------------------------------------|------|------------------------|------|
| t _{c(out)} | Clock output cycle time | | | | 1.87 | 3.75 | ns |
| | | | 267 MHz | | | 80 | |
| | | Infinite and | 300 MHz | Can Figure 2 | | 70 | |
| t _(jitter) | Total cycle jitter over 1, 2, 3, 4, 5, or 6 clock cycles | stopped phase | 356 MHz | See Figure 3 | | 60 | ps |
| | 3, 4, 3, 01 0 0100K cycles | alignment | 400 MHz | | | 50 | |
| | | | 533 MHz ⁽²⁾ | | | 40 | |
| t _(phase) | Phase detector phase error | for distributed loop | | Static phase error ⁽³⁾ | -100 | 100 | ps |
| t _(phase, SSC) | PLL output phase error whe | en tracking SSC | | Dynamic phase error ⁽³⁾ | -100 | 100 | ps |
| I _(DC) | Output duty cycle over 10,0 | 00 cycles | | See Figure 4 | 45% | 55% | |
| | | | 267 MHz | | | 80 | |
| | | Infinite and | 300 MHz | | | 70 | |
| t _(DC, err) | Output cycle-to-cycle duty cycle error | stopped phase | 356 MHz | See Figure 5 | | 60 | ps |
| | dydio difor | alignment | 400 MHz | | | 50 | |
| | | | 533 MHz | | | 50 | |
| t _r , t _f | Output rise and fall times (r voltage) | neasured at 20%-80 | % of output | See Figure 7 | 160 | 400 | ps |
| Δt | Difference between rise and fall times on a single device (20%–80%) t _r -t _r | | See Figure 7 | | 100 | ps | |

STATE TRANSITION LATENCY SPECIFICATIONS

| | PARAMETER | FROM | то | TEST CONDITIONS | MIN | TYP ⁽¹⁾ | MAX | UNIT |
|---------------------------|--|-----------------|-----------|--------------------|-----|--------------------|-----|--------|
| t _(powerup) | Delay time, PWRDNB↑ to CLK/CLKB output settled (excluding t _(DISTLOCK)) | Powerdown | Normal | See Figure 8 | | | 3 | ms |
| | Delay time, PWRDNB↑ to internal PLL and clock are on and settled | Powerdown | Noma | | | | 3 | ms |
| t _(VDDpowerup) | Delay time, power up to CLK/CLKB output settled | V | Normal | See Figure 8 | | | 3 | ms |
| | Delay time, power up to internal PLL and clock are on and settled | V _{DD} | Noma | | | | 3 | 1115 |
| t _(MULT) | MULT0 and MULT1 change to CLK/CLKB output resettled (excluding t _(DISTLOCK)) | Normal | Normal | See Figure 9 | | | 1 | ms |
| t _(CLKON) | STOPB [↑] to CLK/CLKB glitch-free clock edges | CLK Stop | Normal | See Figure 10 | | | 10 | ns |
| t(CLKSETL) | STOPB↑ to CLK/CLKB output settled to within 50 ps of the phase before STOPB was disabled | CLK Stop | Normal | See Figure 10 | | | 20 | cycles |
| t _(CLKOFF) | STOPB↓ to CLK/CLKB output disabled | Normal | CLK Stop | See Figure 10 | | | 5 | ns |
| t _(powerdown) | Delay time, PWRDNB↓ to the device in the power-down mode | Normal | Powerdown | See Figure 8 | | | 1 | ms |
| t _(STOP) | Maximum time in CLKSTOP (STOPB = 0) before reentering normal mode (STOPB = 1) | STOPB | Normal | See Figure 10 | | | 100 | μs |
| t _(ON) | Minimum time in normal mode (STOPB = 1) before reentering CLKSTOP (STOPB = 0) | Normal | CLK Stop | See Figure 10 | 100 | | _ | ms |
| t _(DISTLOCK) | Time from when CLK/CLKB output is settled to when the phase error between SYNCLKN and PCLKM falls within $t_{(phase)}$ | Unlocked | Locked | | | | 5 | ms |

⁽¹⁾ All typical values are at V_{DD} = 3.3 V, T_A = 25°C.

 ⁽¹⁾ All typical values are at V_{DD} = 3.3 V, T_A = 25°C.
 (2) Jitter measurement according to Rambus validation specification
 (3) Assured by design



PARAMETER MEASUREMENT INFORMATION

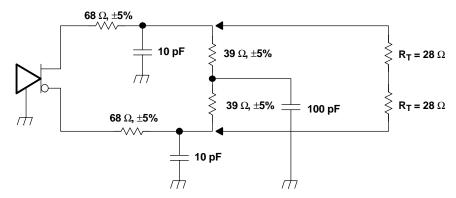
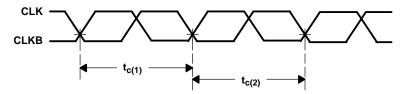
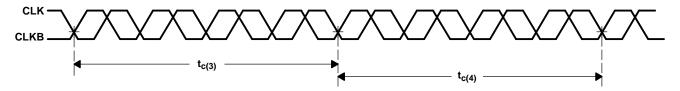


Figure 1. Test Load and Voltage Definitions ($V_{O(STOP)}$, $V_{O(X)}$, V_{O} , V_{OH} , V_{OL})



Cycle-to-cycle jitter = $|t_{c(1)} - t_{c(2)}|$ over 10000 consecutive cycles

Figure 2. Cycle-to-Cycle Jitter



Cycle-to-cycle jitter = $|t_{c(3)} - t_{c(4)}|$ over 10000 consecutive cycles

Figure 3. Short Term Cycle-to-Cycle Jitter Over Four Cycles

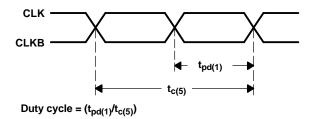


Figure 4. Output Duty Cycle



PARAMETER MEASUREMENT INFORMATION (continued)

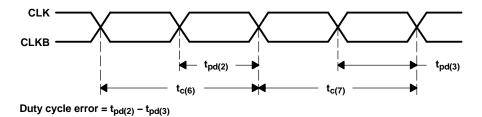


Figure 5. Duty Cycle Error (Cycle-to-Cycle)

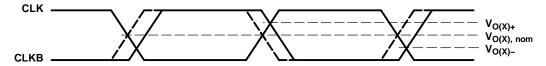


Figure 6. Crossing-Point Voltage

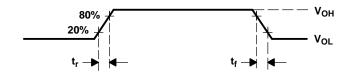


Figure 7. Voltage Waveforms

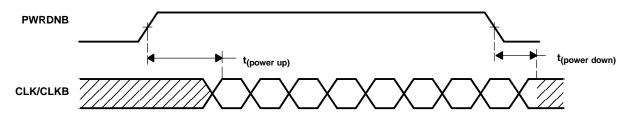


Figure 8. PWRDNB Transition Timings

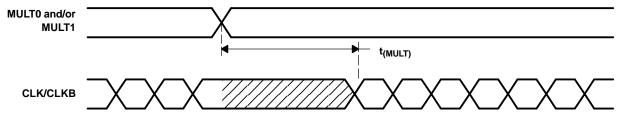
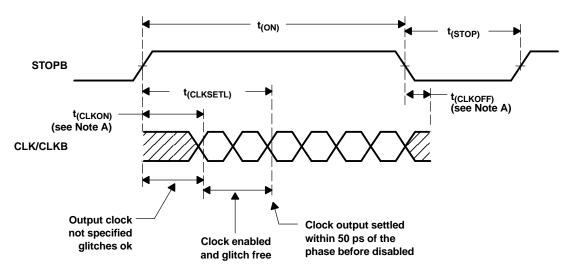


Figure 9. MULT Transition Timings



PARAMETER MEASUREMENT INFORMATION (continued)



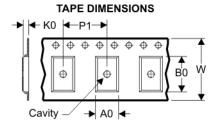
A. $V_{ref} = V_O \pm 200 \text{ mV}$

Figure 10. STOPB Transition Timings



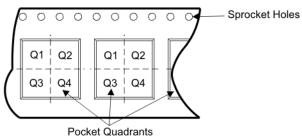
TAPE AND REEL BOX INFORMATION

REEL DIMENSIONS Reel Diameter Reel Widtle



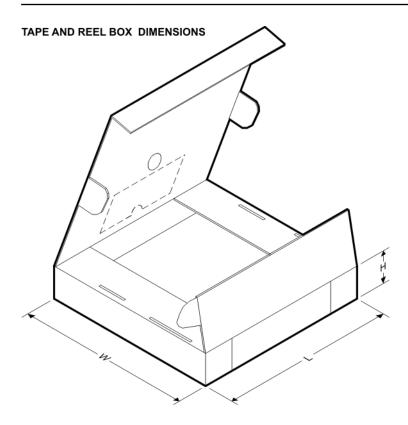
| | Dimension designed to accommodate the component width |
|----|---|
| | Dimension designed to accommodate the component length |
| K0 | Dimension designed to accommodate the component thickness |
| | Overall width of the carrier tape |
| P1 | Pitch between successive cavity centers |

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



| Device | Package | Pins | Site | Reel Diameter (mm) | Reel Width (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|--------------|---------|------|---------|--------------------------|-----------------------|---------|---------|---------|------------|-----------|------------------|
| CDCFR83ADBQR | DBQ | 24 | SITE 41 | 330 | 16 | 6.5 | 9.0 | 2.1 | 8 | 16 | Q1 |

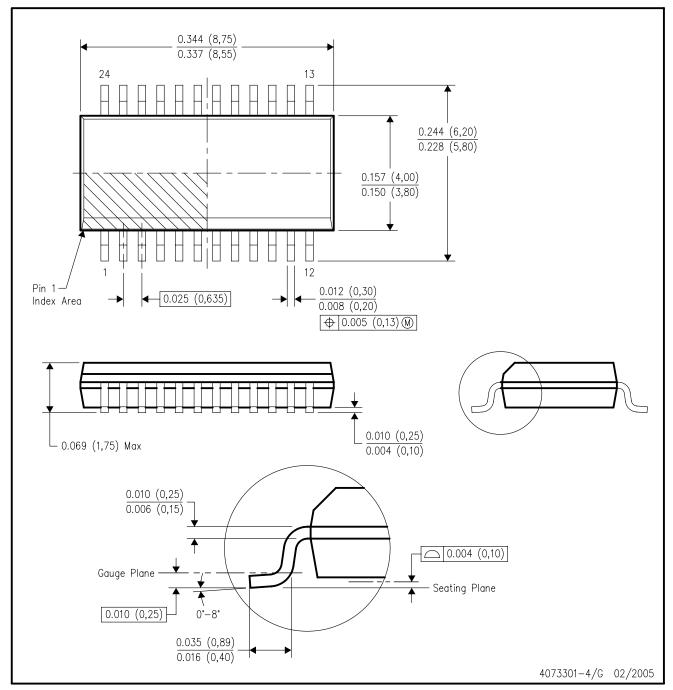




| Device | Package | Pins | Site | Length (mm) | Width (mm) | Height (mm) |
|--------------|---------|------|---------|-------------|------------|-------------|
| CDCFR83ADBQR | DBQ | 24 | SITE 41 | 346.0 | 346.0 | 33.0 |

DBQ (R-PDSO-G24)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15) per side.
- D. Falls within JEDEC MO-137 variation AE.



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